TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor
SCHS191A

January 1998 - Revised May 2000

CD54/74HC597, CD74HCT597

High Speed CMOS Logic 8-Bit Shift Register with Input Storage

Features

- **Buffered Inputs**
- **Asynchronous Parallel Load**
- **Typical f_{MAX} = 60MHz at V_{CC} = 5V, C_L = 15pF, T_A = 25°C**
- **Fanout (Over Temperature Range)**
  - **Standard Outputs . . . . 10 LSTTL Loads**
  - **Bus Driver Outputs . . . . 15 LSTTL Loads**
- **Wide Operating Temperature Range . . . -55°C to 125°C**
- **Balanced Propagation Delay and Transition Times**
- **Significant Power Reduction Compared to LSTTL Logic ICs**
- **HC Types**
  - **2V to 6V Operation**
  - **High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V**
- **HCT Types**
  - **4.5V to 5.5V Operation**
  - **Direct LSTTL Input Logic Compatibility, V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)**
  - **CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL}, V_{OH}**

Description

The ’HC597 and CD74HCT597 are high-speed silicon gate CMOS devices that are pin-compatible with the LSTTL 597 devices. Each device consists of an 8-flip-flop input register and an 8-bit parallel-in/serial-in, serial-out shift register. Each register is controlled by its own clock. A “low” on the parallel load input ($\overline{PL}$) shifts parallel stored data asynchronously into the shift register. A “low” master input ($\overline{MR}$) clears the shift register. Serial input data can also be synchronously shifted through the shift register when $\overline{PL}$ is high.

Ordering Information

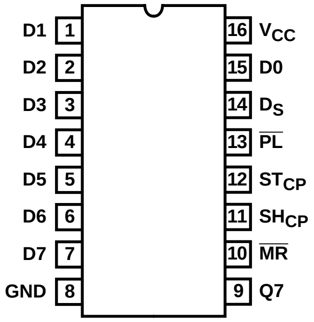
PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC597F3A	-55 to 125	16 Ld CERDIP
CD74HC597E	-55 to 125	16 Ld PDIP
CD74HC597M	-55 to 125	16 Ld SOIC
CD74HCT597E	-55 to 125	16 Ld PDIP
CD74HCT597M	-55 to 125	16 Ld SOIC

NOTES:

1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer and die is available which meets all electrical specifications. Please contact your local TI sales office or customer service for ordering information.

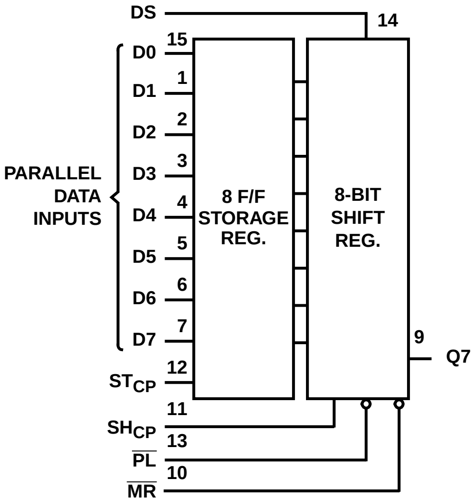
Pinout

CD54HC597
(CERDIP)
CD74HC597, CD74HCT597
(PDIP, SOIC)
TOP VIEW



CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

Functional Diagram



FUNCTION TABLE

ST_{CP}	SH_{CP}	$\overline{PL}$	$\overline{MR}$	FUNCTION
↑	X	X	X	Data Loaded to Input Flip-Flops
↑	X	L	H	Data Loaded from Inputs to Shift Register
No Clock Edge	X	L	H	Data Transferred from Input Flip-Flops to Shift Register
X	X	L	L	Invalid Logic, State of Shift Register Indeterminate when Signals Removed
X	X	H	L	Shift Register Cleared
X	↑	H	H	Shift Register Clocked Qn = Qn-1, Q0 = D_S

NOTE: H = High Voltage Level, L = Low Voltage Level, X = Don't Care, ↑ = Transition from Low to High CP Level

Absolute Maximum Ratings

DC Supply Voltage, V_{CC} . . . . -0.5V to 7V
DC Input Diode Current, I_{IK}
For V_I < -0.5V or V_I > V_{CC} + 0.5V . . . . ±20mA
DC Output Diode Current, I_{OK}
For V_O < -0.5V or V_O > V_{CC} + 0.5V . . . . ±20mA
DC Drain Current, per Output, I_O
For -0.5V < V_O < V_{CC} + 0.5V . . . . ±25mA
DC Output Source or Sink Current per Output Pin, I_O
For V_O > -0.5V or V_O < V_{CC} + 0.5V . . . . ±25mA
DC V_{CC} or Ground Current, I_{CC} . . . . ±50mA

Thermal Information

Thermal Resistance (Typical, Note 3)	θ_{JA} (^{o}C/W)
PDIP Package	90
SOIC Package	160

Maximum Junction Temperature . . . . 150^{o}C
Maximum Storage Temperature Range . . . . -65^{o}C to 150^{o}C
Maximum Lead Temperature (Soldering 10s) . . . . 300^{o}C
(SOIC - Lead Tips Only)

Operating Conditions

Temperature Range, T_A . . . . -55^{o}C to 125^{o}C
Supply Voltage Range, V_{CC}
HC Types . . . . .2V to 6V
DC Input or Output Voltage, V_I, V_O . . . . 0V to V_{CC}
Input Rise and Fall Time
2V . . . . 1000ns (Max)
4.5V. . . . . 500ns (Max)
6V . . . . 400ns (Max)

CAUTION: Stresses above those listed in “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

3. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

		TEST CONDITIONS		V_{CC} (V)	25^{o}C			-40^{o}C TO 85^{o}C		-55^{o}C TO 125^{o}C		
PARAMETER	**SYMBOL**	**V_I (V)**	**I_O (mA)**		**MIN**	**TYP**	**MAX**	**MIN**	**MAX**	**MIN**	**MAX**	**UNITS**
HC TYPES												
High Level Input Voltage	V_{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input Voltage	V_{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V
				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V
			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
			-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V
			4	4.5	-	-	0.26	-	0.33	-	0.4	V
			5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	µA

DC Electrical Specifications **(Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS V_I (V)	TEST CONDITIONS I_O (mA)	V_{CC} (V)	25°C MIN	25°C TYP	25°C MAX	-40°C TO 85°C MIN	-40°C TO 85°C MAX	-55°C TO 125°C MIN	-55°C TO 125°C MAX	UNITS
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	-	8	-	80	-	160	µA
HCT TYPES												
High Level Input Voltage	V_{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V_{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} and GND	0	5.5	-		±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	5.5	-	-	8	-	80	-	160	µA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI_{CC}	V_{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	µA

HCT Input Loading Table

INPUT	UNIT LOADS
D_S	0.2
D_n	0.3
$\overline{PL}$, $\overline{MR}$	1.5
ST_{CP}, SH_{CP}	1.5

NOTE: Unit load is ΔI_{CC} limit specified in DC Electrical Specifications Table, e.g., 360µA max. at 25°C.

Prerequisite for Switching Specifications

PARAMETER	SYMBOL	V_{CC} (V)	25°C MIN	25°C TYP	25°C MAX	-40°C TO 85°C MIN	-40°C TO 85°C TYP	-40°C TO 85°C MAX	-55°C TO 125°C MIN	-55°C TO 125°C TYP	-55°C TO 125°C MAX	UNITS
HC TYPES												
SH_{CP} Frequency	f_{MAX}	2	6	-	-	5	-	-	4	-	-	MHz
		4.5	30	-	-	25	-	-	20	-	-	MHz
		6	35	-	-	29	-	-	23	-	-	MHz

Prerequisite for Switching Specifications **(Continued)**

PARAMETER	SYMBOL	V_{CC} (V)	25°C			-40°C TO 85°C			-55°C TO 125°C			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
SH$_{CP}$ Pulse Width	t_W	2	80	-	-	100	-	-	120	-	-	ns
		4.5	16	-	-	20	-	-	24	-	-	ns
		6	14	-	-	17	-	-	20	-	-	ns
ST$_{CP}$ Pulse Width	t_W	2	60	-	-	75	-	-	90	-	-	ns
		4.5	12	-	-	15	-	-	18	-	-	ns
		6	10	-	-	13	-	-	15	-	-	ns
$\overline{MR}$ Pulse Width	t_W	2	80	-	-	100	-	-	120	-	-	ns
		4.5	16	-	-	20	-	-	24	-	-	ns
		6	14	-	-	17	-	-	20	-	-	ns
$\overline{PL}$ Pulse Width	t_W	2	70	-	-	90	-	-	105	-	-	ns
		4.5	14	-	-	18	-	-	21	-	-	ns
		6	12	-	-	15	-	-	18	-	-	ns
ST$_{CP}$ to SH$_{CP}$ Setup Time	t_{SU}	2	100	-	-	125	-	-	150	-	-	ns
		4.5	20	-	-	25	-	-	30	-	-	ns
		6	17	-	-	21	-	-	26	-	-	ns
D$_S$ to SH$_{CP}$ Setup Time D$_n$ to ST$_{CP}$ Setup Time	t_{SU}	2	50	-	-	65	-	-	75	-	-	ns
		4.5	10	-	-	13	-	-	15	-	-	ns
		6	9	-	-	11	-	-	13	-	-	ns
ST$_{CP}$ to SH$_{CP}$ Setup Time	t_H	2	0	-	-	0	-	-	0	-	-	ns
		4.5	0	-	-	0	-	-	0	-	-	ns
		6	0	-	-	0	-	-	0	-	-	ns
D$_S$ to SH$_{CP}$ Hold Time D$_n$ to ST$_{CP}$ Hold Time	t_H	2	3	-	-	3	-	-	3	-	-	ns
		4.5	3	-	-	3	-	-	3	-	-	ns
		6	3	-	-	3	-	-	3	-	-	ns
MR to SH$_{CP}$ Removal Time	t_{REM}	2	3	-	-	3	-	-	3	-	-	ns
		4.5	3	-	-	3	-	-	3	-	-	ns
		6	3	-	-	3	-	-	3	-	-	ns
HCT TYPES												
SH$_{CP}$ Frequency	f_{MAX}	4.5	25	-	-	20	-	-	16	-	-	MHz
SH$_{CP}$ Pulse Width	t_W	4.5	20	-	-	25	-	-	30	-	-	ns
ST$_{CP}$ Pulse Width	t_W	4.5	13	-	-	16	-	-	20	-	-	ns
$\overline{MR}$ Pulse Width	t_W	4.5	18	-	-	23	-	-	27	-	-	ns
$\overline{PL}$ Pulse Width	t_W	4.5	16	-	-	20	-	-	24	-	-	ns
ST$_{CP}$ to SH$_{CP}$ Setup Time	t_{SU}	4.5	24	-	-	30	-	-	36	-	-	ns

Prerequisite for Switching Specifications (Continued)

PARAMETER	SYMBOL	V_{CC} (V)	25°C			-40°C TO 85°C			-55°C TO 125°C			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
D_S to SH_{CP} Setup Time D_n to ST_{CP} Setup Time	t_H	4.5	10	-	-	13	-	-	15	-	-	ns
ST_{CP} to SH_{CP} Hold Time	t_H	4.5	0	-	-	0	-	-	0	-	-	ns
D_S to SH_{CP} Hold Time D_n to ST_{CP} Hold Time	t_H	4.5	3	-	-	3	-	-	3	-	-	ns
MR to SH_{CP} Removal Time	t_{REM}	4.5	10	-	-	13	-	-	15	-	-	ns

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Propagation Delay SH_{CP} to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	175	-	220	-	265	ns
			4.5	-	-	35	-	44	-	53	ns
		C_L =15pF	5	-	14	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	30	-	37	-	45	ns
$\overline{PL}$ to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	200	-	250	-	300	ns
			4.5	-	-	40	-	50	-	60	ns
		C_L =15pF	5	-	17	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	34	-	43	-	51	ns
ST_{CP} to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	240	-	300	-	360	ns
			4.5	-	-	48	-	60	-	72	ns
		C_L =15pF	5	-	20	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	41	-	51	-	61	ns
$\overline{MR}$ to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	175	-	220	-	265	ns
			4.5	-	-	35	-	44	-	53	ns
		C_L =15pF	5	-	14	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	30	-	37	-	45	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	2	-	-	75	-	95	-	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Input Capacitance	C_I	C_L = 50pF	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance, (Notes 4, 5)	C_{PD}	-	5	-	13.5	-	-	-	-	-	pF
HCT											
Propagation Delay SH_{CP} to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	38	-	48	-	57	ns
		C_L = 15pF	5	-	16	-	-	-	-	-	ns
$\overline{PL}$ to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	48		60		72	ns
		C_L = 15pF	5	-	20	-	-	-	-	-	ns
ST_{CP} to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	56		70		84	ns
		C_L = 15pF	5	-	23	-	-	-	-	-	ns

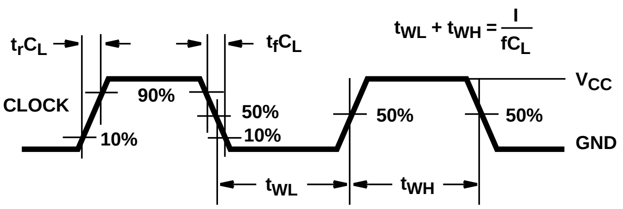
Switching Specifications Input t_r, t_f = 6ns **(Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$\overline{MR}$ to Q7	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	-	44	-	55	-	66	ns
		C_L = 15pF	5	-	18	-	-	-	-	-	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	4.5	-	-	15	-	19	-	22	ns
Input Capacitance	C_I	C_L = 50pF	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance, (Notes 4, 5)	C_{PD}	-	5	-	18.5	-	-	-	-	-	pF

NOTES:

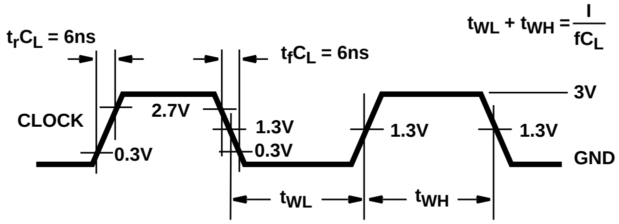
4. C_{PD} is used to determine the dynamic power consumption, per package.
5. $P_D = C_{PD} V_{CC}^2 f_i + \Sigma (C_L V_{CC}^2 f_o)$ where: f_i = Input Frequency, f_o = Output Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms



NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX}, input duty cycle = 50%.

FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH



NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX}, input duty cycle = 50%.

FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

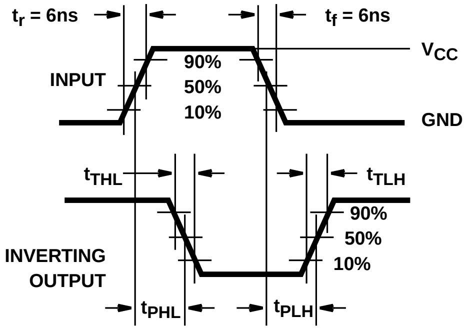


FIGURE 3. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

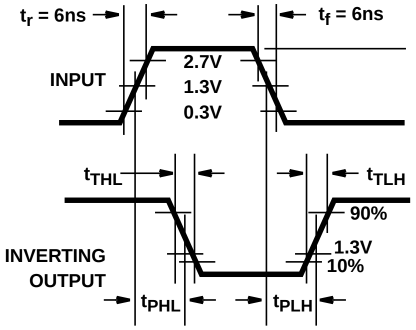


FIGURE 4. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

Test Circuits and Waveforms (Continued)

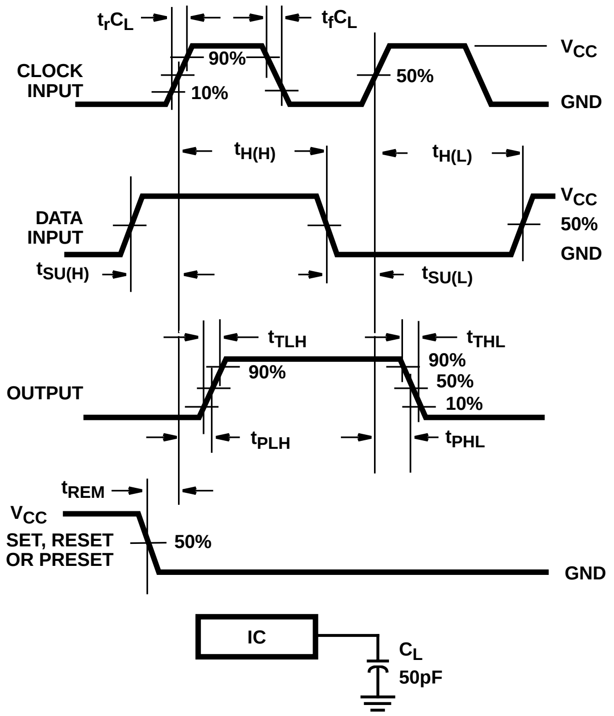


FIGURE 5. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

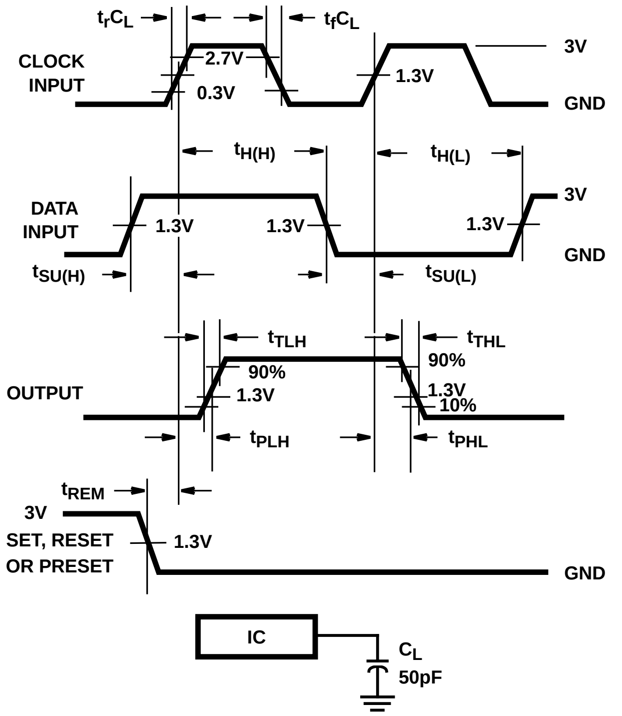
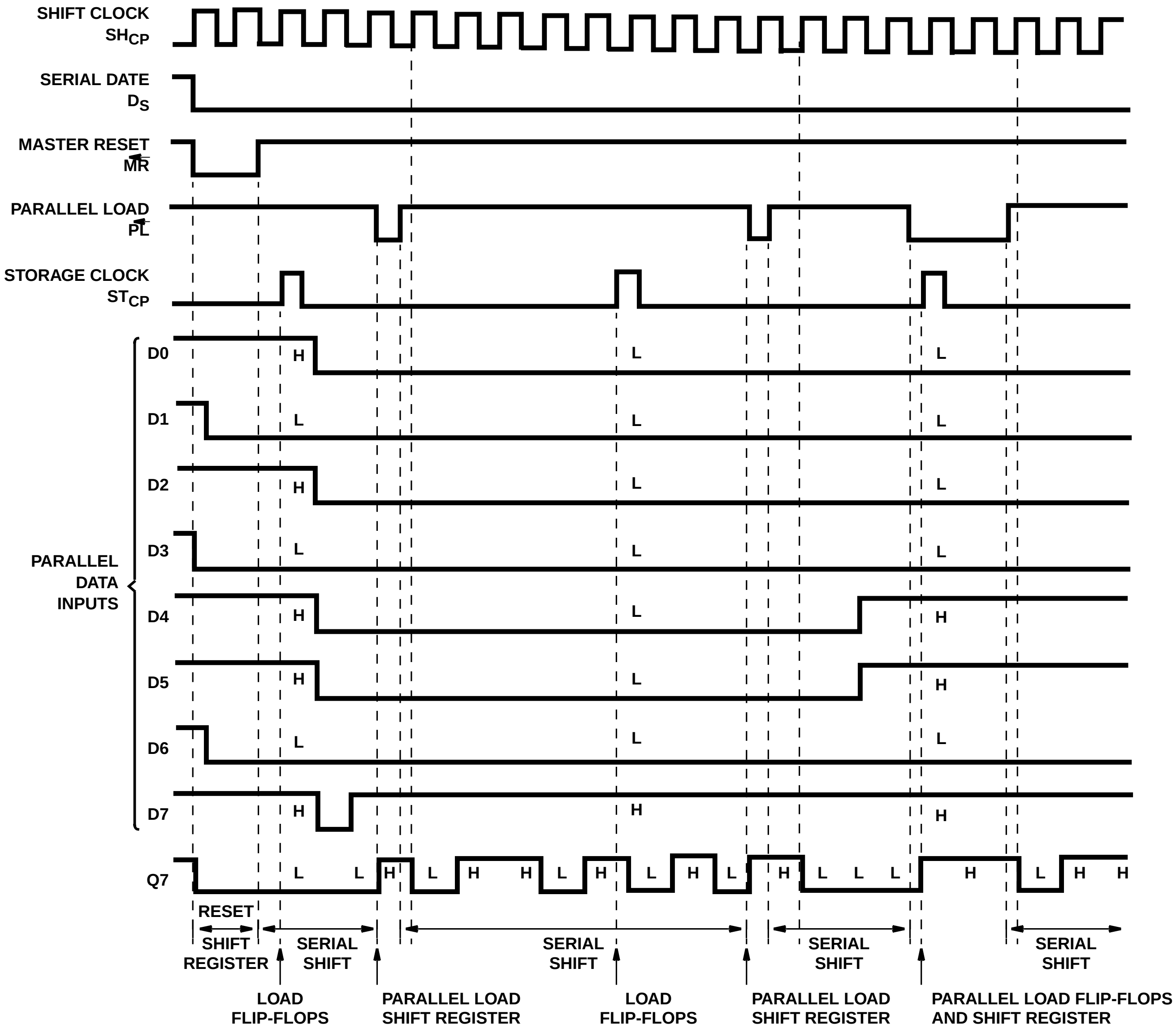


FIGURE 6. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

Timing Diagram



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